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TECHNOLOGY CENTER

Inventor Applicant:

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DU-NOUR

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Serial No.: 09/762,473

Filed: 7 FEB 2001

Group Art Unit: 2877

For: METHOD AND APPARATUS FOR
MEASURING THE THICKNESS OF
A FILM PARTICULARLY OF A
PHOTORESIST FILM ON A
SEMICONDUCTOR SUBSTRATE

Attorney Docket No.: 1639/14

Examiner:

Commissioner of Patents and Trademarks
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

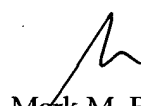
Sir:

Enclosed is PTO Form 1449 which lists citations which may be material to the patentability of the above-identified application. This Information Disclosure Statement is being submitted prior to any Office Action and no fee is required.

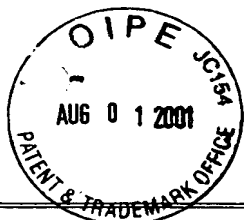
Also enclosed are copies of the references cited. These are being submitted in compliance with the duty of disclosure defined in 37 C.F.R. 1.56. The Examiner is requested to make these citations of official record in this application.

This Information Disclosure Statement Under 37 C.F.R. 1.56 is not to be construed as a representation that a search has been made, that additional matter which is material to the examination of this application does not exist, or that any one or more of these citations constitutes prior art.

Respectfully submitted,


Mark M. Friedman
Attorney for Applicant
Registration No. 33,883

Date: July 29, 2001



Sheet 1 of 1

Form PTO-1449 (Modified)

Atty. Docket No.
1639/14Application No.
09/762,473INFORMATION DISCLOSURE CITATION
IN AN APPLICATION
(USE SEVERAL SHEETS IF NECESSARY)Applicant:
Du-NourFiling Date:
7 February 2001Group Art Unit:
2877

U.S. PATENT DOCUMENTS

	EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
AA							
AB							
AC							
AD							
AE							
AF							
AG							
AH							

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
							YES	NO
AI								
AJ								
AK								
AL								

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AM		Prabhaker S. Naidu, <i>Modern Spectrum Analysis of Time Series</i> , CRC Press 1996
AN		
AO		
AP		

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.